4th Belle II PXD/SVD Workshop and 14th International Workshop on DEPFET Detectors and Applications

Tuesday 22 October 2013

PXD Testsystems - Sem 4a/4b (13:30 - 14:30)

time	[id] title	presenter
13:30	[86] Wafer-Level Testing of long PXD6 Matricies	AVELLA, Paola
13:45	[87] First Results on EMCM Testing	KOFFMANE, Christian LÜTTICKE, Florian
14:15	[88] TB sensor optimization	HÖNIG, Cedric